

**REVISIONS**

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
A	Change to one part-one part number format. Added table III.	91-12-11	M. A. FRYE
B	Changes in accordance with NOR 5962-R036-97.	96-11-26	R. MONNIN
C	Change slew rate value in table I. Remove table III, figures 2, 3, 4, and 5. Update boilerplate. Redrawn. -rrp	00-10-18	R. MONNIN
D	Replaced reference to MIL-STD-973 with reference to MIL-PRF-38535. -rrp	03-05-01	R. MONNIN
E	Make change to the $A_{VS}$ , $+V_{OP}$ , and $-V_{OP}$ test subgroups from 4, 5, and 6 to 1, 2, and 3 as specified under table I. Make change to the $E_n$ and SR test subgroups from 7 to 4 as specified under table I. Make change to $TC_{VIO}$ test subgroups from 8 to 2 and 3 under table I. Make change to paragraph 4.4.1 and table IIA. Update drawing to current requirements. -rrp	11-05-10	C. SAFFLE

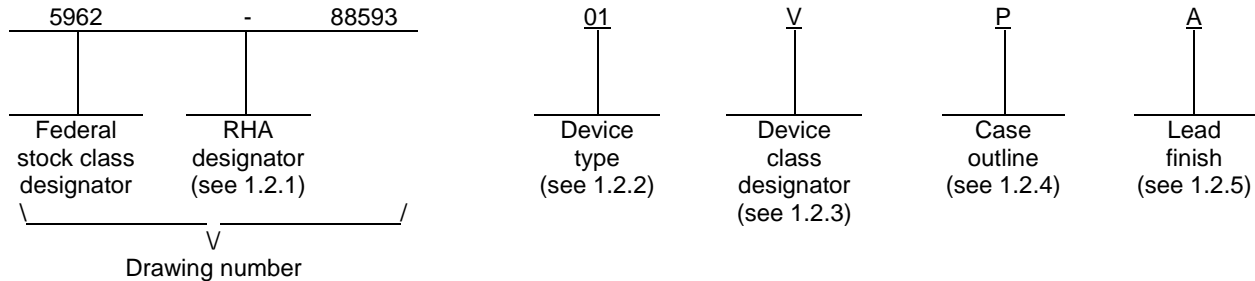
THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

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REV STATUS	REV	E	E	E	E	E	E	E	E	E	E	E								
OF SHEETS	SHEET	1	2	3	4	5	6	7	8	9	10									
PMIC N/A	PREPARED BY GARY ZAHN	<p align="center"><b>DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990</b>  <a href="http://www.dsccl.dla.mil">http://www.dsccl.dla.mil</a></p> <p align="center"><b>MICROCIRCUIT, LINEAR, LOW OFFSET, LOW POWER DUAL OPERATIONAL AMPLIFIER, MONOLITHIC SILICON</b></p>																		
<p align="center"><b>STANDARD MICROCIRCUIT DRAWING</b></p> <p>THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p>	CHECKED BY RAY MONNIN																			
	APPROVED BY D. A. DiCENZO																			
	DRAWING APPROVAL DATE 88-07-25																			
AMSC N/A	REVISION LEVEL E	SIZE A	CAGE CODE <b>67268</b>	<b>5962-88593</b>																
		SHEET		1 OF 10																

1. SCOPE

1.1 Scope. This drawing documents two product assurance class levels consisting of high reliability (device classes Q and M) and space application (device class V). A choice of case outlines and lead finishes are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of Radiation Hardness Assurance (RHA) levels is reflected in the PIN.

1.2 PIN. The PIN is as shown in the following example:



1.2.1 RHA designator. Device classes Q and V RHA marked devices meet the MIL-PRF-38535 specified RHA levels and are marked with the appropriate RHA designator. Device class M RHA marked devices meet the MIL-PRF-38535, appendix A specified RHA levels and are marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 Device type(s). The device type(s) identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	OP200A	Dual, low offset, low power operational amplifier

1.2.3 Device class designator. The device class designator is a single letter identifying the product assurance level as follows:

<u>Device class</u>	<u>Device requirements documentation</u>
M	Vendor self-certification to the requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A
Q or V	Certification and qualification to MIL-PRF-38535

1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
P	GDIP1-T8 or CDIP2-T8	8	Dual-in-line
2	CQCC1-N20	20	Square chip carrier

1.2.5 Lead finish. The lead finish is as specified in MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

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1.3 Absolute maximum ratings. 1/

Supply voltage range .....	±20 V dc
Input voltage .....	Supply voltage
Output short-circuit duration .....	Indefinite
Differential input voltage .....	±30 V dc
Storage temperature range .....	-65°C to +150°C
Lead temperature range (soldering, 60 seconds) .....	+300°C
Junction temperature (T <sub>J</sub> ) .....	+150°C
Thermal resistance, junction-to-case (θ <sub>JC</sub> ) .....	See MIL-STD-1835
Thermal resistance (θ <sub>JA</sub> ):	
Case P .....	119°C/W
Case 2 .....	120°C/W

1.4 Recommended operating conditions.

Supply voltage (V <sub>CC</sub> ) .....	±15 V dc
Source resistance from ground to input terminals (R <sub>S</sub> ) .....	50 Ω
Ambient operating temperature range (T <sub>A</sub> ) .....	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.  
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.  
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <https://assist.daps.dla.mil/quicksearch/> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

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### 3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device classes Q and V shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. The individual item requirements for device class M shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein for device classes Q and V or MIL-PRF-38535, appendix A and herein for device class M.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked. For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device. For RHA product using this option, the RHA designator shall still be marked. Marking for device classes Q and V shall be in accordance with MIL-PRF-38535. Marking for device class M shall be in accordance with MIL-PRF-38535, appendix A.

3.5.1 Certification/compliance mark. The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-PRF-38535. The compliance mark for device class M shall be a "C" as required in MIL-PRF-38535, appendix A.

3.6 Certificate of compliance. For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.6.1 herein). For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6.2 herein). The certificate of compliance submitted to DLA Land and Maritime-VA prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device classes Q and V, the requirements of MIL-PRF-38535 and herein or for device class M, the requirements of MIL-PRF-38535, appendix A and herein.

3.7 Certificate of conformance. A certificate of conformance as required for device classes Q and V in MIL-PRF-38535 or for device class M in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DLA Land and Maritime -VA of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change that affects this drawing.

3.9 Verification and review for device class M. For device class M, DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 49 (see MIL-PRF-38535, appendix A).

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T <sub>A</sub> ≤ +125°C V <sub>CC</sub> = ±15 V, R <sub>S</sub> = 50 Ω unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Input offset voltage	V <sub>IO</sub>		1	01	-75	+75	μV
			2, 3		-125	+125	
Input offset current	I <sub>IO</sub>	V <sub>CM</sub> = 0 V	1	01	-1.0	+1.0	nA
			2, 3		-2.5	+2.5	
Input bias current	±I <sub>IB</sub>	V <sub>CM</sub> = 0 V	1	01	-2.0	+2.0	nA
			2, 3		-5.0	+5.0	
Common mode rejection ratio <u>1/</u>	CMRR	V <sub>CM</sub> = I <sub>VR</sub> = ±11 V	1	01	120		dB
			2, 3		115		
Power supply rejection ratio	PSRR	V <sub>CC</sub> = ±3 V to ±18 V	1	01		1.8	μV/V
			2, 3			3.2	
Supply current no load <u>2/</u>	I <sub>SY</sub>		1	01		1.45	mA
			2, 3			1.55	
Large signal voltage gain	A <sub>VS</sub>	V <sub>OUT</sub> = ±10 V, R <sub>L</sub> = 2 kΩ	1	01	2000		V/mV
			2, 3		1000		
		V <sub>OUT</sub> = ±10 V, R <sub>L</sub> = 10 kΩ	1		5000		
			2, 3		3000		
Output voltage swing	+V <sub>OP</sub>	R <sub>L</sub> = 2 kΩ	1, 2, 3	01	+11		V
		R <sub>L</sub> = 10 kΩ			+12		
	-V <sub>OP</sub>	R <sub>L</sub> = 2 kΩ	1, 2, 3			-11	
		R <sub>L</sub> = 10 kΩ				-12	
Input noise voltage	En	f <sub>O</sub> = 1 Hz to 100 Hz, T <sub>A</sub> = +25°C	4	01		250	nV <sub>rms</sub>
Slew rate	SR	T <sub>A</sub> = +25°C, A <sub>V</sub> = +1	4	01	0.05		V/μs
Input offset voltage temperature coefficient	TC <sub>VIO</sub>	T <sub>A</sub> = +125°C, -55°C	2, 3	01		0.5	μV/°C

1/ I<sub>VR</sub> is defined as the V<sub>CM</sub> range used for the CMRR test.

2/ I<sub>SY</sub> limit = total of all two amplifiers.

**STANDARD  
MICROCIRCUIT DRAWING**

DLA LAND AND MARITIME  
COLUMBUS, OHIO 43218-3990

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Device type	01	
Case outlines	P	2
Terminal number	Terminal symbol	
1	OUT A	NC
2	-IN A	OUT A
3	+IN A	NC
4	-V <sub>CC</sub>	NC
5	+IN B	-IN A
6	-IN B	NC
7	OUT B	+IN A
8	+V <sub>CC</sub>	NC
9	----	NC
10	----	-V <sub>CC</sub>
11	----	NC
12	----	+IN B
13	----	NC
14	----	NC
15	----	-IN B
16	----	NC
17	----	OUT B
18	----	NC
19	----	NC
20	----	+V <sub>CC</sub>

NC = No connection

FIGURE 1. Terminal connections.

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#### 4. VERIFICATION

4.1 Sampling and inspection. For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein. For device class M, sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. For device classes Q and V, screening shall be in accordance with MIL-PRF-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection.

##### 4.2.1 Additional criteria for device class M.

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
  - (2)  $T_A = +125^{\circ}\text{C}$ , minimum.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.

##### 4.2.2 Additional criteria for device classes Q and V.

- a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table IIA herein.
- c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in MIL-PRF-38535, appendix B.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-PRF-38535. Inspections to be performed shall be those specified in MIL-PRF-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.4 Conformance inspection. Technology conformance inspection for classes Q and V shall be in accordance with MIL-PRF-38535 including groups A, B, C, D, and E inspections and as specified herein. Quality conformance inspection for device class M shall be in accordance with MIL-PRF-38535, appendix A and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

##### 4.4.1 Group A inspection.

- a. Tests shall be as specified in table IIA herein.
- b. Subgroups 5, 6, 7, 8, 9, 10, and 11 of table I of method 5005 of MIL-STD-883 shall be omitted.

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TABLE IIA. Electrical test requirements.

Test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)	Subgroups (in accordance with MIL-PRF-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1	1	1
Final electrical parameters (see 4.2)	1,2,3,4 <u>1/</u>	1,2,3,4 <u>1/</u>	1,2,3,4, <u>1/ 2/</u>
Group A test requirements (see 4.4)	1,2,3,4,	1,2,3,4	1,2,3,4
Group C end-point electrical parameters (see 4.4)	1	1	1 <u>2/</u>
Group D end-point electrical parameters (see 4.4)	1	1	1
Group E end-point electrical parameters (see 4.4)	----	----	----

1/ PDA applies to subgroup 1.

2/ Delta limits as specified in table IIB shall be required where specified, and the delta limits shall be computed with reference to the previous endpoint electrical parameters.

Table IIB. 240 hour burn-in and group C end-point electrical parameters. T<sub>A</sub> = +25°C

Test	Limit		Delta		Units
	Min	Max	Min	Max	
V <sub>IO</sub>	-75	75	-50	50	μV
±I <sub>B</sub>	-2	2	-1.5	1.5	nA

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

- a. Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
- b. T<sub>A</sub> = +125°C, minimum.
- c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein).

- a. End-point electrical parameters shall be as specified in table IIA herein.
- b. For device classes Q and V, the devices or test vehicle shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535 for the RHA level being tested. For device class M, the devices shall be subjected to radiation hardness assured tests as specified in MIL-PRF-38535, appendix A for the RHA level being tested. All device classes must meet the postirradiation end-point electrical parameter limits as defined in table I at  $T_A = +25^{\circ}\text{C} \pm 5^{\circ}\text{C}$ , after exposure, to the subgroups specified in table IIA herein.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535 for device classes Q and V or MIL-PRF-38535, appendix A for device class M.

## 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor prepared specification or drawing.

6.1.2 Substitutability. Device class Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users should inform DLA Land and Maritime when a system application requires configuration control and which SMD's are applicable to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DLA Land and Maritime -VA, telephone (614) 692-0544.

6.4 Comments. Comments on this drawing should be directed to DLA Land and Maritime -VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0540.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535 and MIL-HDBK-1331.

6.6 Sources of supply.

6.6.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DLA Land and Maritime -VA and have agreed to this drawing.

6.6.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime -VA.

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APPENDIX

SUBSTITUTION DATA

A.1 SCOPE

A.1.1 Scope. This appendix contains the PIN substitution information to support the one part-one part number system. For new designs, after the date of this document the new PIN shall be used in lieu of the old PIN. For existing designs prior to the date of this document the new PIN can be used in lieu of the old PIN. The appendix is a mandatory part of the specification. The information herein is intended for compliance. The PIN substitution data shall be as follows:

A.2 APPLICABLE DOCUMENTS. This section is not applicable to this appendix.

A.3 SUBSTITUTION DATA

<u>NEW PIN</u>	<u>OLD PIN</u>
5962-8859301MPX	5962-8859301PX
5962-8859301M2X	5962-88593012X

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 11-05-10

Approved sources of supply for SMD 5962-88593 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime -VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at <http://www.dscc.dla.mil/Programs/Smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8859301MPA	24355 (2)	OP-200AZ/883
5962-8859301M2A	24355 (2)	OP-200ARC/883
5962-8859301VPA	24355 (4)	OP200AZ/QMLV
5962-8859301V2A	24355 (4)	OP200ARC/QMLV

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

Vendor name and address

24355

Analog Devices (2)  
 RT 1 Industrial Park  
 P.O. Box 9106  
 Norwood, MA 02062  
 Point of contact: 804 Woburn Street  
 Wilmington, MA 01887-3462

24355

Analog Devices (4)  
 RT 1 Industrial Park  
 P.O. Box 9106  
 Norwood, MA 02062  
 Point of contact: 7910 Triad Center Drive  
 Greensboro, NC 27409-9605

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